Search	Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/727,811	STEFAN ET AL.
Examiner	Art Unit
Benjamin P. Geib	2181

	SEAR	CHED	
Class	Subclass	Date	Examiner
712	22	12/17/2007	BPG
711	101	12/17/2007	BPG
			,

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			-
PGpub te	ext search	12/17/2007	BPG

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Updated EAST search	12/17/2007	BPG
Updated NPL search (Google Scholar and IEEE Xplore)	12/17/2007	BPG
Inventor name search	12/17/2007	BPG
	i.	